Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/695,102	BEHZAD ET AL.	
Examiner	Art Unit	
Henry K. Choe	2817	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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NPL (IEEE)		17	
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